



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Henry A. Hill
Serial No. : 10/616,504
Filed : July 8, 2003
Title : CYCLIC ERROR COMPENSATION IN INTERFEROMETRY SYSTEMS

Art Unit : 2877
Examiner :

Mail Stop Amendment
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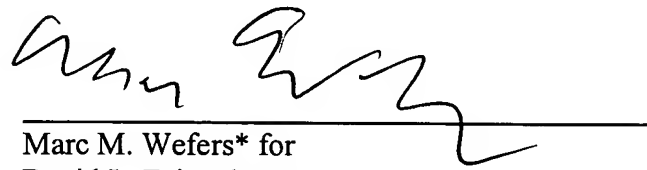
INFORMATION DISCLOSURE STATEMENT

Please consider the references listed on the attached form PTO-1449. Copies of non-patent references are enclosed.

This statement is being filed within three months of the filing date of the application or before the receipt of a first Office Action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 10/28/04


Marc M. Wefers* for
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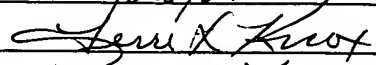
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*See attached document certifying that Marc M. Wefers has limited recognition to practice before the U.S. Patent and Trademark Office under 37 C.F.R. § 10.9(b).

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Substitute Form PTO-1449

U.S. Department of Commerce
Patent and Trademark Office

Attorney's Docket No.

09712-330001

Application No.

10/616,504

**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

Applicant

Henry A. Hill

Filing Date

July 8, 2003

Group Art Unit

2877

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	4,413,908	11/1983	Abrams et al.			
	AB	4,948,254	08/1990	Ishida			
	AC	5,151,749	09/29/1992	Tanimoto et al.			
	AD	5,249,016	9/1993	Tanaka, Hiroshi			
	AE	5,331,400	07/1994	Wilkening et al.			
	AF	5,404,222	04/1995	Lis			
	AG	5,432,603	07/1995	Sentoku et al.			
	AH	5,483,343	01/1996	Iwamoto et al.			
	AI	5,491,550	02/13/1996	Dabbs			
	AJ	5,663,793	09/1997	de Groot			
	AK	5,724,136	03/03/1998	Zanoni			
	AL	5,757,160	05/26/1998	Dreuzer			
	AM	5,764,361	06/09/1998	Kato et al.			
	AN	5,790,253	08/04/1998	Kamiya			
	AO	5,850,291	12/1998	Tsutsui, Shinji			
	AP	5,940,180	08/1999	Ostby			
	AQ	5,969,800	10/1999	Makinouchi			
	AR	6,008,902	12/1999	Rinn			
	AS	6,020,964	02/01/2000	Loopstra et al.			
	AT	6,046,792	04/04/2000	Van Der Werf et al.			
	AU	6,134,007	10/17/2000	Naraki et al.			
	AV	6,137,574	10/2000	Hill			
	AW	6,160,619	12/2000	Magome			
	AX	6,181,420	01/2001	Badami et al.			
	AY	6,201,609	03/2001	Hill et al.			
	AZ	6,271,923	08/07/2001	Hill			
	AAA	6,304,318	10/16/2001	Matsumoto			

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-330001	Application No. 10/616,504
	Applicant Henry A. Hill		
	Filing Date July 8, 2003	Group Art Unit 2877	

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	ABB	6,313,918	11/06/2001	Hill et al.			
	ACC	6,687,013	02/2004	Isshiki et al.			
	ADD	6,747,744	06/08/2004	Hill			
	AEE	6,806,961	10/19/2004	Hill			
	AFF	2002/0048026 A1	04/25/2002	Isshiki et al.			

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AGG	JP 7-351078	12/1995	Japan (Abstract Only)				
	AHH	JP 8-117083	04/1996	Japan (Abstract Only)				
	AII	JP 10-260009	09/29/1998	Japan (with Abstract)				X
	AJJ							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AKK	Badami V.G. et al., "Investigation of Nonlinearity in High Accuracy Heterodyne Laser Interferometry," 1997 PROCEEDINGS, Vol. 16, pp. 153-156.
	ALL	Bennett, S.J. <u>Optics Communications</u> , 4:6, pp. 428-430, 1972
	AMM	Bobroff, N., "Recent Advances in Displacement Measuring Interferometry," MEASUREMENT SCIENCE & TECHNOLOGY, Vol. 4, No. 9, September 1993, pp. 907-926.
	ANN	Hines, B. et al., "Sub-Nanometer Laser Metrology - Some Techniques and Models," JET PROPULSION LABORATORY, CALIFORNIA INSTITUTE OF TECHNOLOGY, pp. 1195-1204.
	AOO	Oka K. et al., "Polarization Heterodyne Interferometry Using Another Local Oscillator Beam," OPTICS COMMUNICATIONS, 92 (1992), 1-5.
	APP	Wu, C.M. et al., "Analytical Modeling of the Periodic Nonlinearity in Heterodyne Interferometry," APPLIED OPTICS, Vol. 37, No. 28, 1 October 1998, pp. 6696-6700.
	AQQ	

Examiner Signature	Date Considered
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